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Authors	Bolger, Ciara T.;Farrell, Richard A.;Hughes, Gareth M.;Morris, Michael A.;Petkov, Nikolay;Holmes, Justin D.
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Pore Directionality and Correlation Lengths of Mesoporous Silica Channels Aligned by Physical Epitaxy

Ciara T. Bolger^{†,ϕ}, Richard A. Farrell^{†,ϕ}, Gareth M. Hughes[§], Michael A. Morris^{†,ϕ}, Nikolay
Petkov^{†,*} and Justin D. Holmes^{†,ϕ*}.

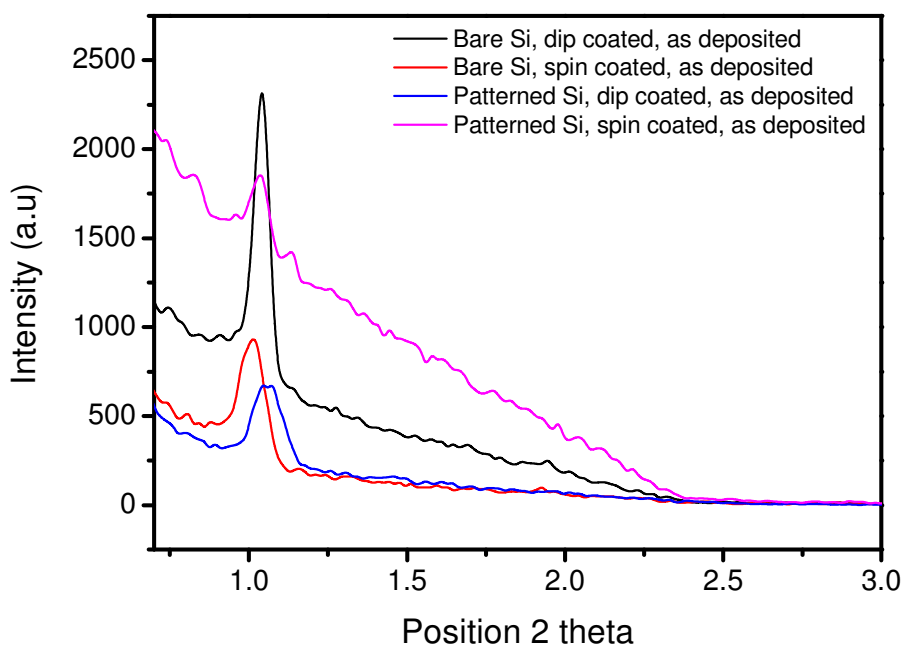


Figure S1 Reflective X-ray Diffraction patterns of spin- and dip-coated mesoporous films on bare and patterned silicon substrates